## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Carl W. Orthlieb, et al. Art Unit : 2131

Serial No.: 10/080,923 Examiner: Christopher A. Revak

Filed : February 21, 2002 Conf. No. : 7784
Title : APPLICATION RIGHTS ENABLING

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## MAIL STOP AMENDMENT Commissioner for Patents

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## INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request. A copy of a communication from a foreign patent office in a counterpart annification is also enclosed.

This statement is being filed before the receipt of a first Office Action after the filing of a Request for Continued Examination under 37 C.F.R. §1.114. Please apply any charges or credits to Denosit Account No. 06-1050.

Respectfully submitted,

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07844-518001	Application No. 10/080,923	
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Carl W. Orthlieb, et al.		
		Filing Date Echnology 21, 2002	Group Art Unit	

	Foreig	n Patent Do	cuments or F	ublished Foreign	Patent A	Application	ns	
Examiner Desig.	Document	Publication	Country or			Translation		
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AA	00/54128	09/14/2000	PCT				
	AB	01/61508	08/23/2001	PCT				

Other Documents (include Author, Title, Date, and Place of Publication)				
Examiner Initial	Desig.	Document		
	AC	Ortiz, S "Email Protection Advances with New Technologies", Computer IEEE Service Center, Los Alamitos, CA, vol. 33, no. 1, XP000951701; ISSN: 0018-9162, pages 21-23, January 2000.		
	AD			
	AE			
	AF			

Examiner Signature	Date Considered			
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.				